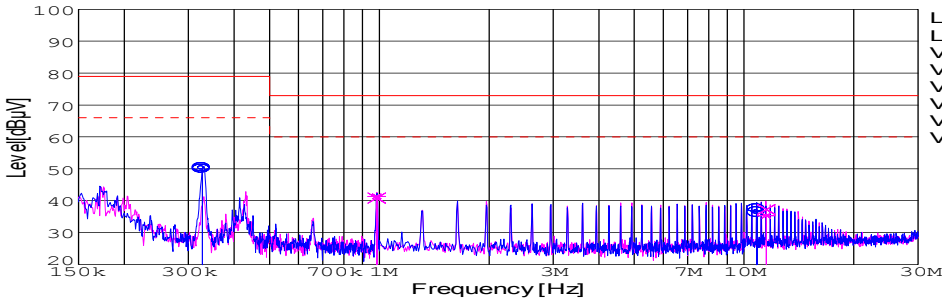
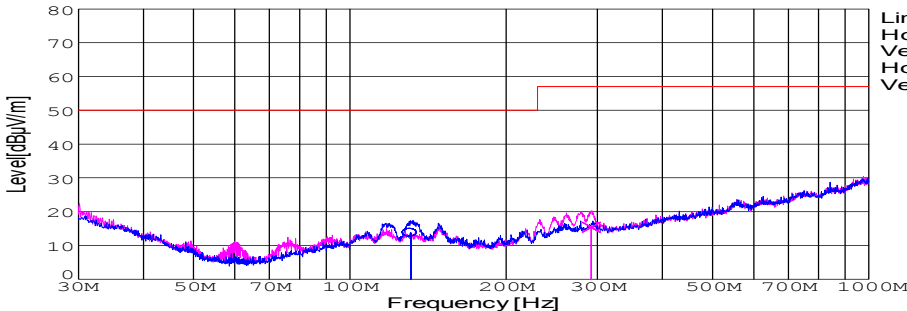


DATA SHEET							Date	10-Mar-05		
Model	SUCW64815						Temp.	25 degreeC		
Test	EMI Line conduction & Radiated emission						Humid.	45 %RH		
							Tested by	Y.Hirose		
LINE CONDUCTION										
Model Name : SUCW64815			Temp. : 25							
Model No. :			Humi. : 45							
Serial No. :			Date : 2005/3/10 12:00							
Points : 4			Test Equip. : R3132,ESPC							
Detector : PEAK/QP/Ave.			Comment : Y.Hirose							
Line Mode : VA/VB			+15V0.2A							
Power Supply : DC 48V			-15V0.2A							
Limit1: [EN 55022] Class A(QP)										
Limit2: [EN 55022] Class A(Ave.)										
							Limit1(QP) Limit2(Ave.) VA(PEAK) VB(PEAK) VA(QP) VA(Ave.) VB(QP) VB(Ave.)			
							DC 48V +15V0.2A -15V0.2A			
Frequency [MHz]	Meter Reading (Ave.) [dBuV]	Meter Reading (QP) [dBuV]	Factor [dB]	Level(Ave.) [dBuV]	Level(QP) [dBuV]	Line	Limit(Ave.) [dBuV]	Limit(QP) [dBuV]	Margin(Ave.) [dB]	Margin(QP) [dB]
0.3276	40.6	40	9.8	50.4	49.8	VA	66	79	15.6	29.2
10.8353	26.2	27.4	10.1	36.3	37.5	VA	60	73	23.7	35.5
0.9843	31.5	30.9	9.9	41.4	40.8	VB	60	73	18.6	32.2
11.4954	25.2	27.2	10.1	35.3	37.3	VB	60	73	24.7	35.7

RADIATED EMISSION										
Model Name : SUCW64815			Temp. : 25							
Model No. :			Humi. : 45							
Serial No. :			Date : 2005/3/10 12:57							
Points : 2			Test Equip. : R3132,ESPC							
Detector : PEAK/QP			Comment : Y.Hirose							
Polarization : Hori. & Vert.			+15V0.2A							
Power Supply : DC 48V			-15V0.2A							
Limit: [EN 55022] Class A<3m>										
							Limit(QP) Horizontal(PEAK) Vertical(PEAK) Horizontal(QP) Vertical(QP)			
							DC 48V +15V0.2A -15V0.2A			
Frequency [MHz]	MeterReading (QP) [dBuV]	Ant. Type	Antenna Factor [dB/m]	Cable & Preamp [dB]	Level(QP) [dBuV/m]	Angle [°]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]
130.942	34.2	BL	11.2	-31.6	13.8	329	156	Hori.	50	36.2
291.913	33.5	BL	12.9	-31	15.4	310	106	Vert.	57	41.6

# COSEL

## Conditions

Test : EMI  
Model Name : SUCS/SUCW 648□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

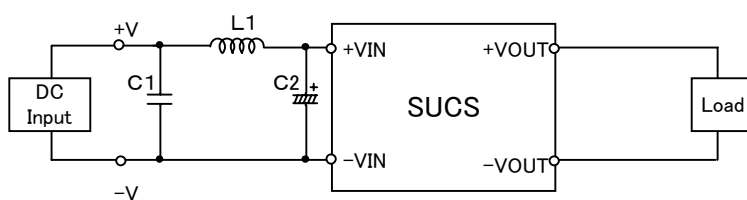


Fig.1 Testing circuitry 1

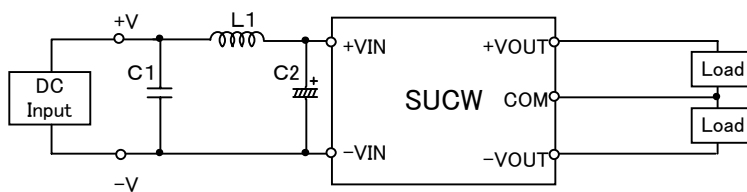


Fig.2 Testing circuitry 2

L1 :	6.8 $\mu$ H	CY3H-6R8	(KORIN ELECTRONICS)
C1 :	100V 1 $\mu$ F	C3225JB2A105M	(TDK)
C2 :	100V 47 $\mu$ F	UPW2A470M	(NICHICON)